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		Coifman, R.R. and Y. Meyer, "Remarque	Coifman, R.R. and Y. Meyer, "Remarques sur l'analyse de Fourier à fenêtre", Compte rendus de l'Academie odes Sciences,									
C.C.	AR		seria I: Mathematique, Vol. 312, pp. 259-261, 1991. (French)									
	 ^*	C.K. Chui, ed., Wavelets: A Tutorial in T	heory and A	pplication, Academ	nic Press, "I	ocal Sine and C	osine Bases o	f Coifman				
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Include copy of this form with next communication to Applicant.												

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		Coifman, R.R. and Y. Meyer, "Local Sine and Cosine Bases of Coifman and Meyer and the Construction of Smooth									
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